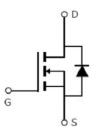


Main Product Characteristics:

V _{DSS}	300V
R _{DS} (on)	45mΩ(typ.)
I _D	50A 1







TO-247

Marking and Pin Assignment

Schematic Diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute Max Rating:

Symbol	Parameter	Max.	Units
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V ①	50	
I _D @ TC = 100°C	Continuous Drain Current, V _{GS} @ 10V ①	31	А
I _{DM}	M Pulsed Drain Current @		-
	Power Dissipation 3	390	W
P _D @TC = 25°C	Linear Derating Factor	3.12	W/°C
V _{DS}	Drain-Source Voltage	300	V
V _{GS}	Gate-to-Source Voltage		V
E _{AS}	Single Pulse Avalanche Energy @ L=60mH		mJ
I _{AS}	Avalanche Current @ L=60mH	12.2	А
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C



Thermal Resistance

Symbol	Characteristics	Тур.	Max.	Units
R _{θJC}	Junction-to-case ③	—	0.32	°C /W
Р	Junction-to-ambient (t $\leq 10s)$ (4)	—	62	°C /W
$R_{\theta JA}$	Junction-to-Ambient (PCB mounted, steady-state) ④	_	40	°CW

Electrical Characteristics $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	300	_	—	V	$V_{GS} = 0V, I_D = 250 \mu A$
R _{DS(on)}	Static Drain-to-Source on-resistance	_	45	65	mΩ	$V_{GS}=10V, I_{D}=25A$
V _{GS(th)}	Gate threshold voltage	2	_	4	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$
1	Drain to Source lookage ourrent	_	_	1		$V_{DS} = 300 V, V_{GS} = 0 V$
IDSS	Drain-to-Source leakage current	_	_	50	μA	T _J = 125°C
	Cata to Source forward lookage		—	100	54	V _{GS} =30V
I _{GSS}	Gate-to-Source forward leakage		_	-100	nA	V _{GS} = -30V
Qg	Total gate charge	_	124	_		I _D = 40A,
Q _{gs}	Gate-to-Source charge	_	28	_	nC	V _{DS} =240V,
Q _{gd}	Gate-to-Drain("Miller") charge	_	50	_	-	$V_{GS} = 10V$
t _{d(on)}	Turn-on delay time	_	62	—		
t _r	Rise time	_	165	_		V_{GS} =10V, V_{DS} =150V,
t _{d(off)}	Turn-Off delay time	_	303	_	nS	$R_{GEN}=25\Omega$
t _f	Fall time	_	144	_	1	I _D =40A
Ciss	Input capacitance	_	5723	_		$V_{GS} = 0V$
Coss	Output capacitance	_	725	_	pF	V _{DS} = 25V
C _{rss}	Reverse transfer capacitance	_	32	—	1	f = 800kHz

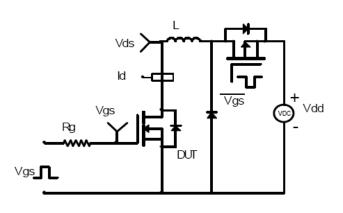
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			MOSFET symbol		
I _S	(Body Diode)		50 ①		A	showing the
	Pulsed Source Current		100	•	integral reverse	
I _{SM}	(Body Diode)		_	192	A	p-n junction diode.
V _{SD}	Diode Forward Voltage		0.66	1.5	V	I _S =1A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	-	333	-	nS	$T_J = 25^{\circ}C, I_F = 38.5A,$
Q _{rr}	Reverse Recovery Charge		2.5		μC	di/dt = 100A/µs



Test circuits and Waveforms

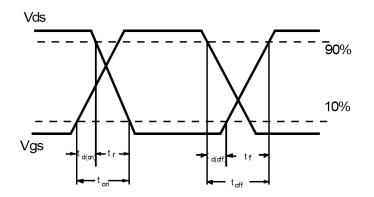
EAS Test Circuit:



Switching Time Test Circuit:

Switching Waveforms:

Gate charge test circuit:



Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- O Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- (4) The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



Typical electrical and thermal characteristics

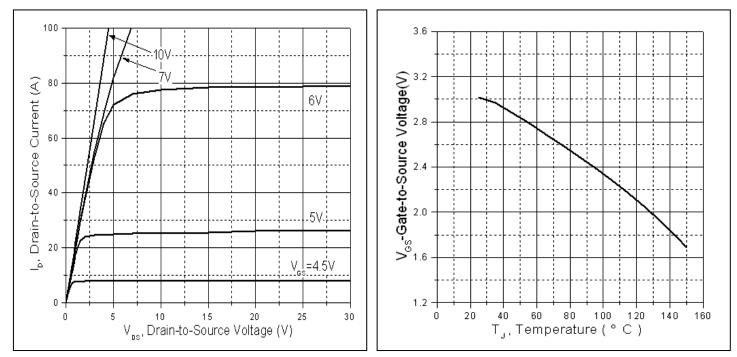
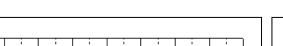


Figure 1.Typical Output Characteristics



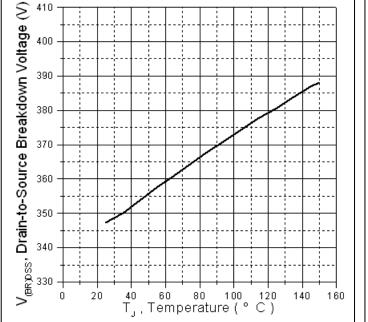
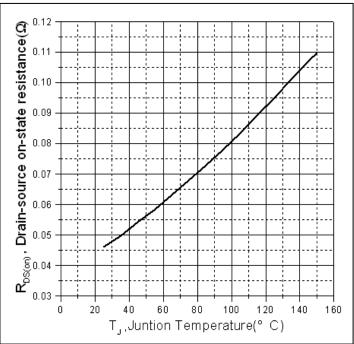


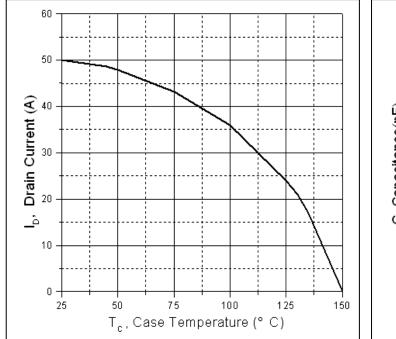
Figure 3. Drain-to-Source Breakdown Voltage Vs. Case Temperature

Figure 2. Gate to source cut-off voltage









Typical electrical and thermal characteristics



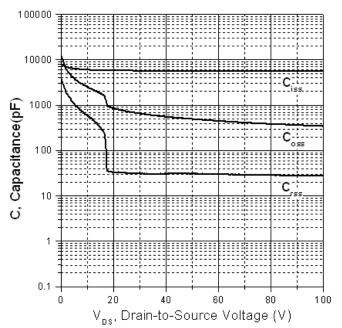
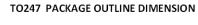
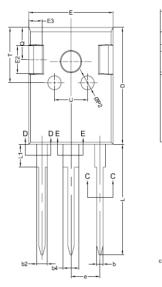


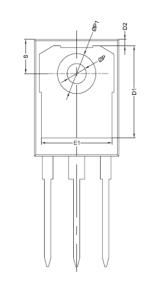
Figure 6. Typical Capacitance Vs. Drain-to-Source Voltage

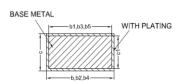


Mechanical Data:









Sumbol	Din	nension In Millime	ters	Dimension In Inches			
Symbol	Min	Nom	Max	Min	Nom	Max	
Α	4.900	5.000	5.100	0.193	0.197	0.201	
A1	2.300	2.405	2.510	0.091	0.095	0.099	
A2	1.900	2.000	2.100	0.075	0.079	0.083	
b	1.160	-	1.260	0.046	-	0.050	
b1	1.150	1.185	1.220	0.045	0.047	0.048	
b2	1.960	-	2.060	0.077	-	0.081	
b3	1.950	1.985	2.020	0.077	0.078	0.080	
b4	2.960	-	3.060	0.117	-	0.120	
b5	2.950	2.985	3.020	0.116	0.118	0.119	
C	0.590	-	0.660	0.023	-	0.026	
c1	0.580	0.600	0.620	0.023	0.024	0.024	
D	20.900	21.000	21.100	0.823	0.827	0.831	
D1	16.250	16.550	16.850	0.640	0.652	0.663	
D2	1.050	1.200	1.350	0.041	0.047	0.053	
Ε	15.700	15.800	15.900	0.618	0.622	0.626	
E1	13.100	13.300	13.500	0.516	0.524	0.531	
E2	4.900	5.000	5.100	0.193	0.197	0.201	
E3	2.400	2.500	2.600	0.094	0.098	0.102	
е		5.44BSC		0.214BSC			
L	19.800	19.950	20.100	0.780	0.785	0.791	
L1	-	-	4.300	-	-	0.169	
Р	3.500	3.600	3.700	0.138	0.142	0.146	
P1	-	-	7.400	-	-	0.291	
P2	2.400	2.500	2.600	0.094	0.098	0.102	
Q	5.600	-	6.000	0.220	-	0.236	
S		6.15BSC			0.242BSC		
Т	9.800	-	10.200	0.386	-	0.402	
U	6.000	-	6.400	0.236	-	0.252	



Ordering and Marking Information

Device Marking: SSPL50N30H	
Package (Available)	
TO-247	
Operating Temperature Range	
C : -55 to 150 ⁰C	

Devices per Unit

Package Type	Units/ Tube	Tubes/Inner Box	Units/Inner Box	Boxes/Carton	Units/Carton Box
				Box	
TO247	30	8	240	5	1200

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =150℃ @ 80% of	168 hours	3 lots x 77 devices
Temperature	Max V _{DSS} /V _{CES} /VR	500 hours	
Reverse		1000 hours	
Bias(HTRB)			
High	T _j =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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